

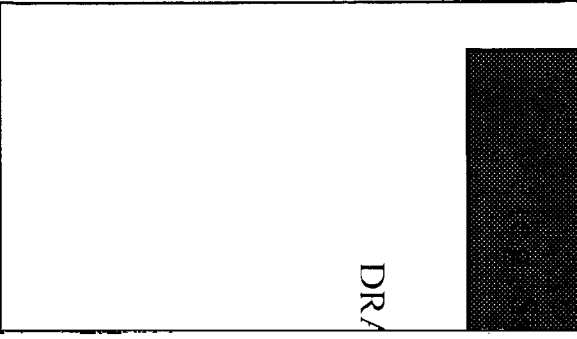
Interviews Conducted

- DI
 - DI
 - JE
 - DI
- engineers
plant managers
participants
users

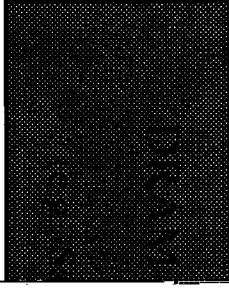


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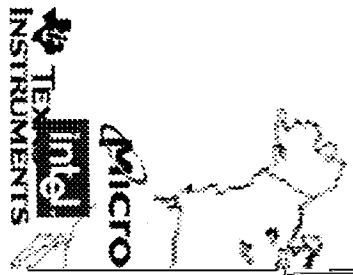


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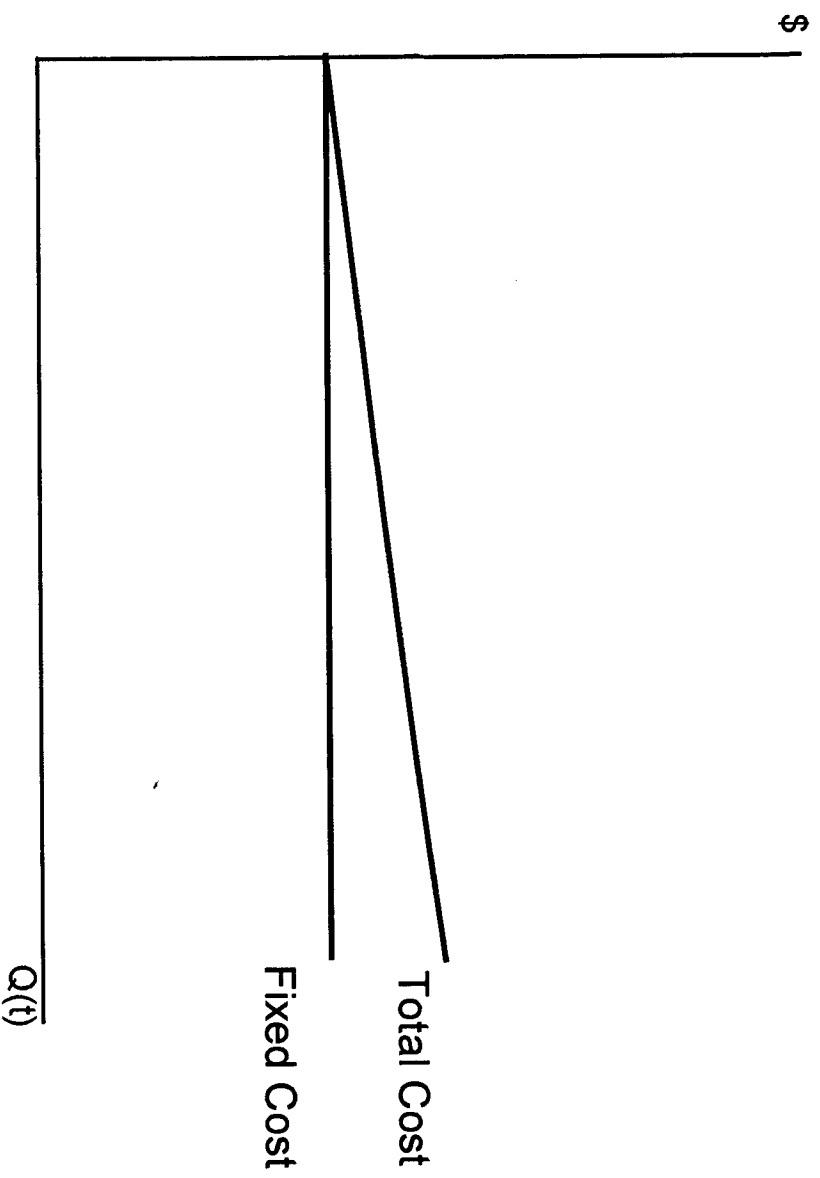
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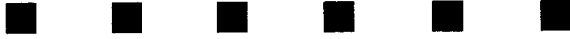


Economics of DRAM Production

- **High fixed costs**
- **Volatility / cyclicality**
- **Intense price competition**
- **Maximize capacity utilization / yield**
- **Intense cost cutting**

Total Cost and Fixed Cost





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Economic Fa



- Open, consense
- Open availabili
- Royalties
- Implementatio
- Manufacturing
- Evolutionary / r

JEDDEC: IP Disclosure

- Preference to avoid patents
- Early disclosure / good faith
- Disclosure applies to patents / patent applications relevant to JEDDEC standards / work
- RAND: mandatory for JEDDEC; voluntary for members
- Valid technical justification

Latency

- Fixed CAS late
- Presented at J
 - NEC Presenta
- Cost impact
 - “A fixed DRAM feature to the E point of view, ti every function and burst lengt
 - Potentially high *Macri Trial Tes*

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Latency Technology Market

- Programmable in read command
 - Not presented at JEDEC
 - Mitsubishi Presentation at 42.3 Committee Meeting (12/91) (Programming Burst Length)
 - Cost impact
 - “The advantage would be that you would eliminate register and the circuitry required to decode special commands and put that information into the mode so it would make the part potentially smaller and
Jacob Trial Testimony at 5391-92

Latenc

- Set by fuses
- Presented at
 - Cray Presen
- Cost impact
 - "It would be eliminate the design and t fuse, you wo instead of ha would be a c *Testimony a*

Burst Leng

- Fixed burst lengt
- Presented at JE
 - NEC Presentatio
- Cost impact
 - "A fixed DRAM i
 - feature to the DR
 - point of view, th
 - every function ir
 - and burst length

Burst Length Technology Market

- Programmable by pin strapping
 - Not presented at JEDEC
 - Micron Presentation at Special 42.3 Committee Meeting (7/00) (Programming CAS latency)
 - Cost impact
 - “The cost associated with each of those was relatively similar in the large scheme of things, so I would say from a cost standpoint, that was a large factor in our decision.” *Kellogg Trial Testimony at 5132*

Burst Length Technology N

- Programmable in read command
- Presented at JEDEC
 - Mitsubishi Presentation at 42.3 Committee N (12/91)
- Cost impact
 - “Well, again, you would get rid of the mode 1 therefore the circuitry required to initialize it, make the part simpler to design and test and cheaper to manufacture.” *Jacob Trial Testin*

Burst L

- Burst interr
- In SDRAM
proposed
- Cost impa
 - “I mean,
burst inte
DRAM de
words, th

Data Acceleration Techn

- Double the clock frequency
 - Presented at JEDEC
 - VLSI Presentation at 42.3 Committe
 - Cost impact
 - “Well, a faster single edge clock has benefits in that we don't have to pay called duty cycle. Duty cycle -- you pulse that is high and a pulse that is is the length of the high pulse versus pulse, and managing that is very diff conditions. It sounds simple; very c clocking doesn't have that issue at a benefit to single edge clocking.” *Mac*

4779-4780

Clock Synch

- Put the DLL on the
- Presented at JEDEC
 - Samsung Presenta
- Cost impact
 - “You would eliminate the power consumption, die size of the DRAM, cost of the DRAM. DRAM because you that would be part of because it would not take less time. And uncertainty than simply itself, so you could than just using an c at 5446-5447

Clock Synch Technology Market

- PLL/DLL on module
 - PLL on DIMM in registered DIMMs and in Kentron QBM DIMM
 - Cost impact
 - “You eliminate the on-chip DLL from the DRAM, thereby reducing its power consumption, reducing its cost, reducing the design time. ... [Y]ou then move that design complexity onto a special DLL chip that goes onto the module, so you would be trading one for the other.” *Jacob Trial Testimony at 5450*

Clock Synch Te

- Vernier
- Presented at JEDEC
 - Synclink Presentation at
- Cost impact
 - "It's simpler to design th:
potentially more skew th
achieve higher data rate
Jacob Trial Testimony a

Clock Synchron

- No DLL at all
- Presented at JEDEC
 - SGI Presentation at
- Cost impact
 - “Q. Now, what, if a DQS data strobe chip DLLs?”
 - A. Well, you would your design simpler design would be sn forth.”
- *Jacob Trial Testim*

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- Cost
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Reasons Why Conduc

- Distorted JEDEC:
concealing (or mis
information
- Excluded alternati
technologies
- Entailed a conscie
enforceability of p.

If Rambus Had I No R

- Rambus documents st
business model
- Rambus wanted flexibi
rates
- Rambus wanted RDR
- Not issuing RAND lette
- Without RAND letter, J
standard

Exclusion

Rambus's Cc

- By not disclosing IP ex incurred risk of having I
- Implication is that Raml benefits from non-disclo
- Like predatory pricing, t absent expected benefi competition